# SONY

# ICX058AK

# 1/3-inch CCD Image Sensor for PAL Color Camera

# Description

The ICX058AK is an interline CCD solid-state image sensor suitable for PAL color video cameras. High resolution is achieved through the use of Ye, Cy, Mg, and G complementary color mosaic filters. At the same time, high sensitivity and low dark current are achieved through the adoption of HAD (Hole-Accumulation Diode) sensors.

This chip features a field period readout system and an electronic shutter with variable charge-storage time.



- High resolution, high sensitivity and low dark current
- Continuous variable-speed shutter 1/60s (Typ.), 1/100s to 1/10000s
- Low smear
- Excellent antiblooming characteristics
- Ye, Cy, Mg, and G complementary color mosaic filters on chip

5V drive

- Horizontal register: 5V drive 123
- Reset gate:

# **Device Structure**

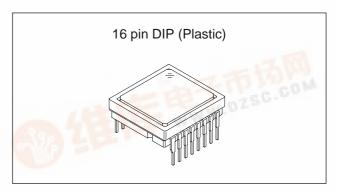
- Optical size:
- Number of effective pixels:
- Number of total pixels:
- Interline CCD image sensor
- Chip size:
- Unit cell size:
- Optical black:
- Number of dummy bits:
- Substrate material:

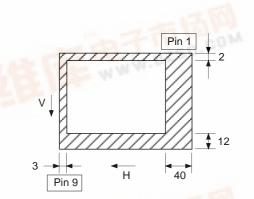
1/3-inch format

- 768 (H)  $\times$  494 (V) approx. 380K pixels
- 811 (H)  $\times$  508 (V) approx. 410K pixels
- 6.00mm (H) × 4.96mm (V)
  - 6.35µm (H) × 7.40µm (V)

Horizontal (H) direction: Front 3 pixels, rear 40 pixels Vertical (V) direction: Front 12 pixels, rear 2 pixels Horizontal 22

Vertical 1 (even field only) Silicon



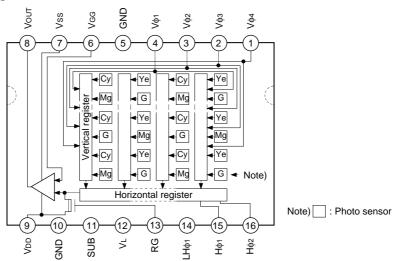


Optical black position (Top View)

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# **Block Diagram and Pin Configuration**

(Top View)



# **Pin Description**

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	Vø4	Vertical register transfer clock	9	Vdd	Output amplifier drain supply
2	Vфз	Vertical register transfer clock	10	GND	GND
3	Vø2	Vertical register transfer clock	11	SUB	Substrate (Overflow drain)
4	Vφ1	Vertical register transfer clock	12	VL	Protective transistor bias
5	GND	GND	13	RG	Reset gate clock
6	Vgg	Output amplifier gate bias	14	LHø1	Horizontal register final stage transfer clock
7	Vss	Output amplifier source	15	Ηφ1	Horizontal register transfer clock
8	Vout	Signal output	16	Hø2	Horizontal register transfer clock

# **Absolute Maximum Ratings**

	Item	Ratings	Unit	Remarks
Substrate voltage SUB – C	GND	-0.3 to +55	V	
Supply voltage	Vdd, Vout, Vss – GND	-0.3 to +18	V	
Supply voltage	Vdd, Vout, Vss – SUB	-55 to +10	V	
Vertical clock input voltage	Vφ1, Vφ2, Vφ3, Vφ4 – GND	-15 to +20	V	
venical clock input voltage	Vφ1, Vφ2, Vφ3, Vφ4 – SUB	to +10	V	
Voltage difference betwee	n vertical clock input pins	to +15	V	*1
Voltage difference betwee	n horizontal clock input pins	to +17	V	
Ηφ1, Ηφ2 Vφ4		-17 to +17	V	
Ηφ1, Ηφ2, LΗφ1, RG, Vgg-	GND	-10 to +15	V	
Ηφ1, Ηφ2, LΗφ1, RG, Vgg-	SUB	–55 to +10	V	
VL-SUB		-65 to +0.3	V	
Vφ1, Vφ2, Vφ3, Vφ4, VDD, VC	DUT – VL	-0.3 to +30	V	
RG – VL		-0.3 to +24	V	
Vgg, Vss, Hø1, Hø2, LHø1 –	- VL	-0.3 to +20	V	
Storage temperature		-30 to +80	°C	
Operating temperature		-10 to +60	°C	

\*1 +27V (Max.) when clock width < 10 $\mu$ s, clock duty factor < 0.1%.

### **Bias Conditions**

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain voltage	Vdd	14.55	15.0	15.45	V	
Output amplifier gate voltage	Vgg	3.8	4.2	4.65	V	
Output amplifier source	Vss		ounded w 0Ω resist			±5%
Substrate voltage adjustment range	Vsub	9.0		18.5	V	*1
Fluctuation range after substrate voltage adjustment	ΔVsub	-3		+3	%	
Reset gate clock voltage adjustment range	Vrgl	1.0		4.0	V	*1 *6
Fluctuation range after reset gate clock voltage adjustment	$\Delta V$ rgl	-3		+3	%	
Protective transistor bias	VL		*2	•		

#### **DC Characteristics**

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain current	ldd		5		mA	
Input current	lin1			1	μA	*3
Input current	lin2			10	μA	*4

\*1 Indications of substrate voltage (Vsub) · reset gate clock voltage (VRGL) setting value.

The setting values of substrate voltage and reset gate clock voltage are indicated on the back of the image sensor by a special code. Adjust substrate voltage ( $V_{SUB}$ ) and reset gate clock voltage ( $V_{RGL}$ ) to the indicated voltage. Fluctuation range after adjustment is ±3%.

VSUB code one character indication

VRGL code one character indication

VRGL code VSUB code

Code and optimal setting correspond to each other as follows.

Vrgl code	1	2	3	4	5	6	7
Optimal setting	1.0	1.5	2.0	2.5	3.0	3.5	4.0

Vsub code	E	f	G	h	J	Κ	L	m	Ν	Р	Q	R	S	Т	U	V	W	Х	Y	Ζ
Optimal setting	9.0	9.5	10.0	10.5	11.0	11.5	12.0	12.5	13.0	13.5	14.0	14.5	15.0	15.5	16.0	16.5	17.0	17.5	18.0	18.5

<Example> "5L"  $\rightarrow$  VRGL = 3.0V VSUB = 12.0V

\*2 VL setting is the VvL voltage of the vertical transfer clock waveform. \*3 1) Current to each pin when 18V is applied to VpD Volt. Vss and  $\frac{1}{2}$ 

- 1) Current to each pin when 18V is applied to VDD, VOUT, Vss and SUB pins, while pins that are not tested are grounded.
  - 2) Current to each pin when 20V is applied sequentially to Vφ1, Vφ2, Vφ3 and Vφ4 pins, while pins that are not tested are grounded. However, 20V is applied to SUB pin.
  - 3) Current to each pin when 15V is applied sequentially to RG, LH\otherson, H\otherson 1, H\otherson 2, LH\otherson 2, LH\otherson 1, H\otherson 2, LH\otherson 2, LH\othe
  - 4) Current to VL pin when 30V is applied to Vφ1, Vφ2, Vφ3, Vφ4, VDD and VOUT pins or when, 24V is applied to RG pin or when, 20V is applied to VGG, Vss, Hφ1, Hφ2 and LHφ1 pins, while VL pin is grounded. However, GND and SUB pins are left open.
- <sup>\*4</sup> Current to SUB pin when 55V is applied to SUB pin, while pins that are not tested are grounded.

n ↑↑

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# **Clock Voltage Conditions**

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Readout clock voltage	Vvт	14.55	15.0	15.45	V	1	
	Vvh1, Vvh2	-0.05	0	0.05	V	2	Vvн = (Vvн1 + Vvн2)/2
	Vvнз, Vvн4	-0.2	0	0.05	V	2	
	Vvl1, Vvl2, Vvl3, Vvl4	-9.0	-8.5	-8.0	V	2	$V_{VL} = (V_{VL3} + V_{VL4})/2$
	Vφv	7.8	8.5	9.05	V	2	$V\phi = V + n - V + n (n = 1 \text{ to } 4)$
Vertical transfer clock	I Vvh1 – Vvh2 I			0.1	V	2	
voltage	Vvнз — Vvн	-0.25		0.1	V	2	
	Vvн4 — Vvн	-0.25		0.1	V	2	
	Vvнн			0.5	V	2	High-level coupling
	Vvhl			0.5	V	2	High-level coupling
	Vvlh			0.5	V	2	Low-level coupling
	Vvll			0.5	V	2	Low-level coupling
Horizontal transfer	Vфн, Vфlн	4.75	5.0	5.25	V	3	*5
clock voltage	Vhl, Vlhl	-0.05	0	0.05	V	3	*5
Reset gate clock	Vørg	4.5	5.0	5.5	V	4	*6
voltage	Vrglh – Vrgll			0.8	V	4	Low-level coupling
Substrate clock voltage	Vфsuв	22.5	23.5	24.5	V	5	

\*5 The horizontal final stage transfer clock input pin LH<sup>\u03c41</sup> is connected to the horizontal transfer clock input pin H<sup>\u03c41</sup>.

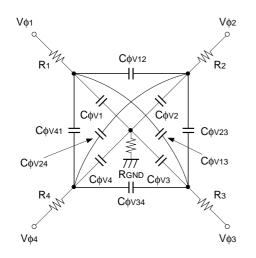
\*6 The reset gate clock voltage need not be adjusted when reset gate clock is driven when the specifications are as given below. In this case, the reset gate clock voltage setting indicated on the back of the image sensor has not significance.

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Reset gate clock	Vrgl	-0.2	0	0.2	V	4	
voltage	Vørg	8.5	9.0	9.5	V	4	

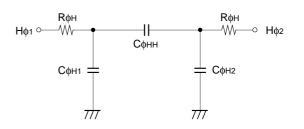
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# **Clock Equivalent Circuit Constant**

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Capacitance between vertical transfer	Cφν1, Cφν3		1000		pF	
clock and GND	<b>C</b> φν2, <b>C</b> φν4		560		pF	
	Сфv12, Сфv34		470		pF	
Capacitance between vertical transfer	Сф∨23, Сф∨41		330		pF	
clocks	Сф∨13		220		pF	
	Сф∨24		100		pF	
Capacitance between horizontal transfer clock and GND	Сфн1, Сфн2		47		pF	
Capacitance between horizontal transfer clocks	Сфнн		43		pF	
Capacitance between horizontal final stage transfer clock and GND	Сфін		8		pF	
Capacitance between reset gate clock and GND	Cộrg		8		pF	
Capacitance between substrate clock and GND	Сфѕив		270		pF	
Vertical transfer clock series resistor	R1, R2, R3, R4		80		Ω	
Vertical transfer clock ground resistor	Rgnd		15		Ω	
Horizontal transfer clock series resistor	Rфн		15		Ω	



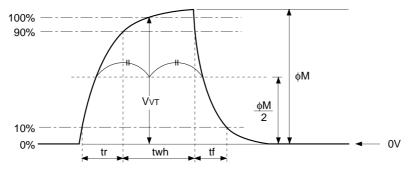
Vertical transfer clock equivalent circuit



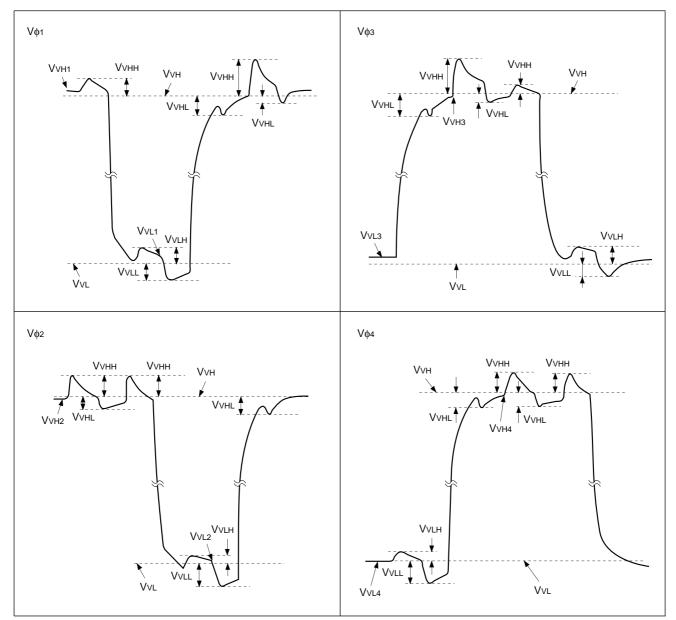
Horizontal transfer clock equivalent circuit

# **Drive Clock Waveform Conditions**

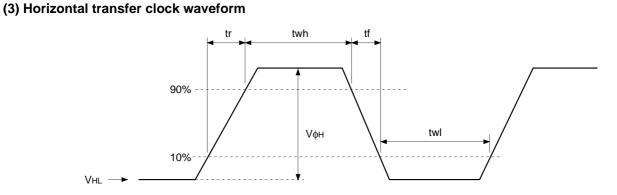
# (1) Readout clock waveform



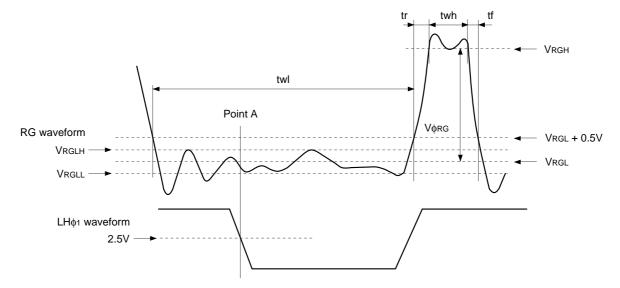
### (2) Vertical transfer clock waveform



 $V_{VH} = (V_{VH1} + V_{VH2})/2$  $V_{VL} = (V_{VL3} + V_{VL4})/2$  $V_{\varphi V} = V_{VHN} - V_{VLN} (n = 1 \text{ to } 4)$ 



## (4) Reset gate clock waveform



VRGLH is the maximum value and VRGLL is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG.

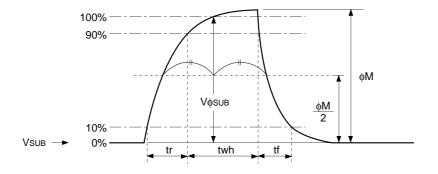
In addition,  $\mathsf{V}\mathsf{RGL}$  is the average value of  $\mathsf{V}\mathsf{RGLH}$  and  $\mathsf{V}\mathsf{RGLL}.$ 

VRGL = (VRGLH + VRGLL)/2

Assuming VRGH is the minimum value during the interval twh, then:

 $V\phi RG = VRGH - VRGL$ 

#### (5) Substrate clock waveform



# **Clock Switching Characteristics**

**Note)** Because the horizontal final stage transfer clock  $LH\phi_1$  is connected to the horizontal transfer clock  $H\phi_1$ , specifications will be the same as  $H\phi_1$ .

	ltem	Symbol		twh			twl			tr			tf		Unit	Remarks
	nem	Gymbol	Min.	Тур.	Max.	Onit	Remarks									
Rea	dout clock	VT	2.3	2.5						0.5			0.5		μs	During readout
Vert cloc	ical transfer k	Vφ1, Vφ2, Vφ3, Vφ4										15		250	ns	*1
×	During	Hø1, LHø1	18	24		19.5	26			10	17.5		10	17.5	ns	*2
r clc	imaging	Hø2	21	26		19	24			10	15		10	15	115	-
Horizontal transfer clock	During parallel-serial	Hø1, LHø1		5.38						0.01			0.01			
tra ⊢	conversion	Hø2					5.38			0.01			0.01		μs	
Res	et gate clock	φrg	11	13			51			3			3		ns	
Sub	strate clock	φsub	1.5	1.8							0.5			0.5	μs	During drain charge

\*1 When vertical transfer clock driver CXD1250 is used.

\*<sup>2</sup> tf ≥ tr − 2ns, and the cross-point voltage (V<sub>CR</sub>) for the H $\phi_1$  · LH $\phi_1$  rising side of the H $\phi_1$  · LH $\phi_1$  and H $\phi_2$  waveforms must be at least 2.5V.

ltem	Symbol		two	Unit	Remarks		
lien	Symbol	Min.	Тур.	Max.	Unit	Remarks	
Horizontal transfer clock	Ηφ1 · LΗφ1, Ηφ2	16	20		ns	*3	

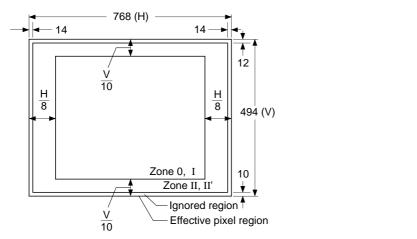
\*3 The overlap period for twh and twl of horizontal transfer clocks  $H\phi_1 \cdot LH\phi_1$  and  $H\phi_2$  is two.

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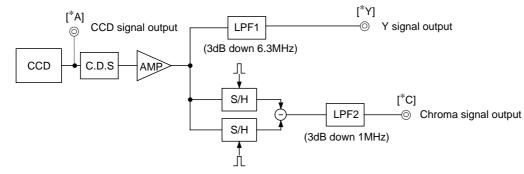
# **Image Sensor Characteristics**

Image Sensor Characterist	ics						(Ta = 25°C)
Item	Symbol	Min.	Тур.	Max.	Unit	Measurement method	Remarks
Sensitivity	S	270	340		mV	1	
Saturation signal	Ysat	600			mV	2	Ta = 60°C
Smear	Sm		0.009	0.015	%	3	
Video signal shading	SHy			20	%	4	Zone 0, I
Video signal shading	Sily			25	%	4	Zone 0 to II'
Uniformity between video	ΔSr			10	%	5	
signal channels	ΔSb			10	%	5	
Dark signal	Ydt			2	mV	6	Ta = 60°C
Dark signal shading	ΔYdt			1	mV	7	Ta = 60°C
Flicker Y	Fy			2	%	8	
Flicker R-Y	Fcr			5	%	8	
Flicker B-Y	Fcb			5	%	8	
Line crawl R	Lcr			3	%	9	
Line crawl G	Lcg			3	%	9	
Line crawl B	Lcb			3	%	9	
Line crawl W	Lcw			3	%	9	
Lag	Lag			0.5	%	10	

#### Zone Definition of Video Signal Shading



# **Measurement System**

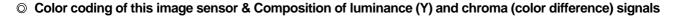


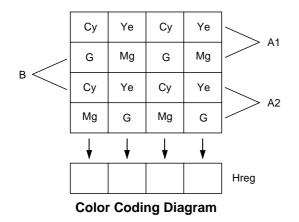
**Note)** Adjust the amplifier gain so that the gain between  $[^*A]$  and  $[^*Y]$  and between  $[^*A]$  and  $[^*C]$  equal 1.

#### **Image Sensor Characteristics Measurement Method**

#### O Measurement conditions

- In the following measurements, the substrate voltage and the reset gate clock voltage are set to the values indicated on the device, and the device drive conditions are at the typical values of the bias and clock voltage conditions.
- 2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black level (OB) is used as the reference for the signal output, which is taken as the value of Y signal output or chroma signal output of the measurement system.





As shown in the left figure, fields are read out. The charge is mixed by pairs such as A1 and A2 in the A field. (pairs such as B in the B field)

As a result, the sequence of charges output as signals from the horizontal shift register (Hreg) is, for line A1, (G + Cy), (Mg + Ye), (G + Cy), and (Mg + Ye).

These signals are processed to form the Y signal and chroma (color difference) signal. The Y signal is formed by adding adjacent signals, and the chroma signal is formed by subtracting adjacent signals. In other words, the approximation:

$$Y = {(G + Cy) + (Mg + Ye)} \times 1/2$$

is used for the Y signal, and the approximation:

$$R - Y = \{(Mg + Ye) - (G + Cy)\}\$$
  
= {2R - G}

is used for the chroma (color difference) signal. For line A2, the signals output from Hreg in sequence are

$$(Mg + Cy), (G + Ye), (Mg + Cy), (G + Ye).$$

The Y signal is formed from these signals as follows:

 $Y = \{(G + Ye) + (Mg + Cy)\} \times 1/2$ = 1/2 {2B + 3G + 2R}

This is balanced since it is formed in the same way as for line A1.

In a like manner, the chroma (color difference) signal is approximated as follows:

$$-(B - Y) = \{(G + Ye) - (Mg + Cy)\}\$$
  
=  $-\{2B - G\}$ 

In other words, the chroma signal can be retrieved according to the sequence of lines from R - Y and - (B - Y) in alternation. This is also true for the B field.

### O Definition of standard imaging conditions

#### 1) Standard imaging condition I:

Use a pattern box (luminance 706cd/m<sup>2</sup>, color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter and image at F5.6. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity.

#### 2) Standard imaging condition II:

Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter. The luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm.

1. Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/250s, measure the Y signal (Ys) at the center of the screen and substitute the value into the following formula.

$$S = Ys \times \frac{250}{60} [mV]$$

2. Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with average value of the Y signal output, 200mV, measure the minimum value of the Y signal.

3. Smear

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity to 500 times the intensity with average value of the Y signal output, 200mV. When the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value YSm [mV] of the Y signal output and substitute the value into the following formula.

$$Sm = \frac{YSm}{200} \times \frac{1}{500} \times \frac{1}{10} \times 100 \, [\%] \, (1/10V \text{ method conversion value})$$

4. Video signal shading

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity so that the average value of the Y signal output is 200mV. Then measure the maximum (Ymax [mV]) and minimum (Ymin [mV]) values of the Y signal and substitute the values into the following formula.

SHy = (Ymax – Ymin)/200 × 100 [%]

5. Uniformity between video signal channels

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then measure the maximum (Crmax, Cbmax [mV]) and minimum (Crmin, Cbmin [mV]) values of the R – Y and B – Y channels of the chroma signal and substitute the values into the following formula.

 $\Delta Sr = | (Crmax - Crmin)/200 | \times 100 [\%]$  $\Delta Sb = | (Cbmax - Cbmin)/200 | \times 100 [\%]$ 

6. Dark signal

Measure the average value of the Y signal output (Ydt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

### 7. Dark signal shading

After measuring 6, measure the maximum (Ydmax [mV]) and minimum (Ydmin [mV]) values of the Y signal output and substitute the values into the following formula.

 $\Delta$ Ydt = Ydmax - Ydmin [mV]

8. Flicker

#### 1) Fy

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then measure the difference in the signal level between fields ( $\Delta$ Yf [mV]). Then substitute the value into the following formula.

$$Fy = (\Delta Yf/200) \times 100 [\%]$$

#### 2) Fcr, Fcb

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, insert an R or B filter, and then measure both the difference in the signal level between fields of the chroma signal ( $\Delta$ Cr,  $\Delta$ Cb) as well as the average value of the chroma signal output (CAr, CAb). Substitute the values into the following formula.

 $Fci = (\Delta Ci/CAi) \times 100 [\%] (i = r, b)$ 

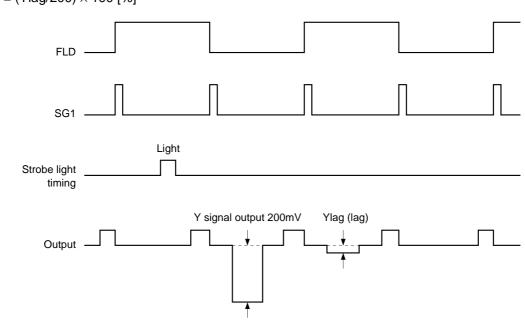
9. Line crawls

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then insert a white subject and R, G, and B filters and measure the difference between Y signal lines for the same field ( $\Delta$ Ylw,  $\Delta$ Ylr,  $\Delta$ Ylg,  $\Delta$ Ylb [mV]). Substitute the values into the following formula.

Lci =  $(\Delta Y li/200) \times 100 [\%]$  (i = w, r, g, b)

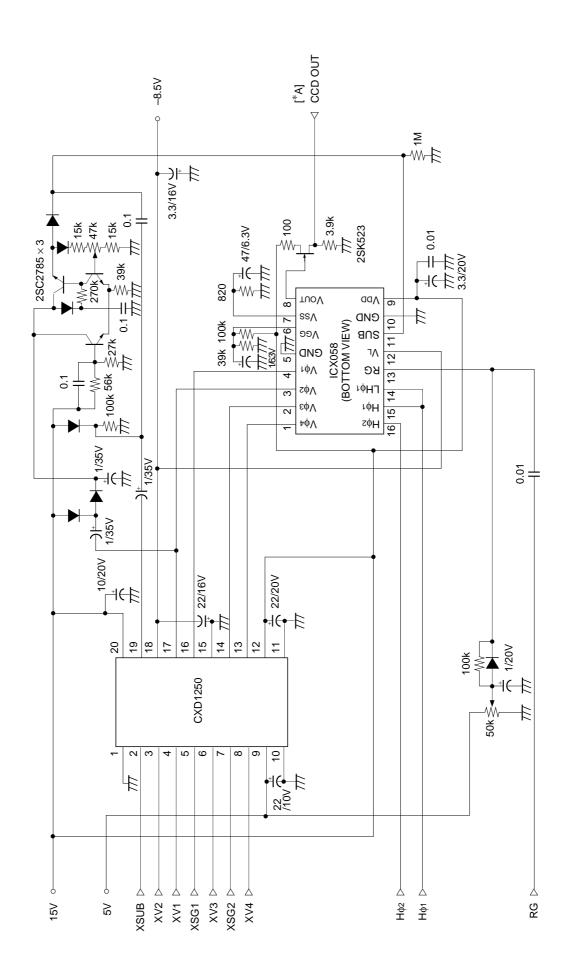
#### 10. Lag

Adjust the Y signal output value generated by strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Ylag). Substitute the value into the following formula.



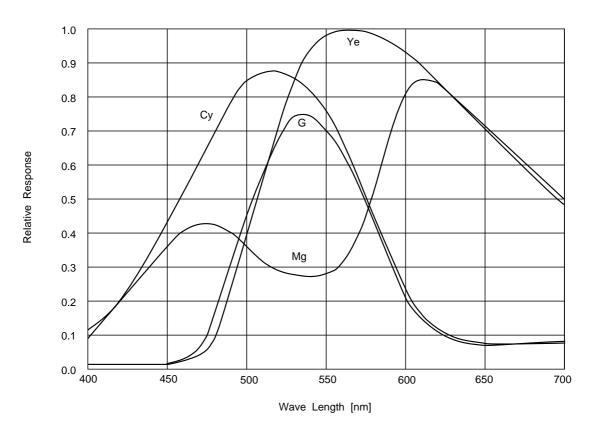
- 12 -

 $Lag = (Ylag/200) \times 100 [\%]$ 

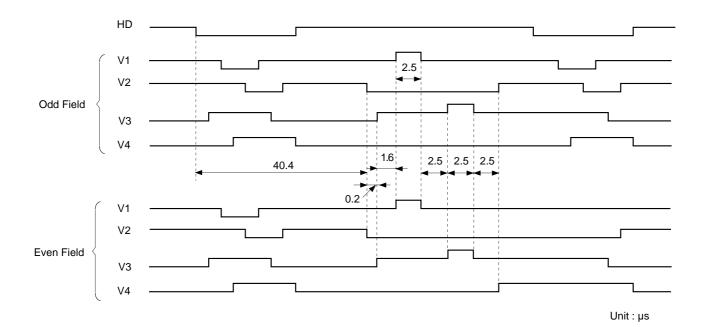


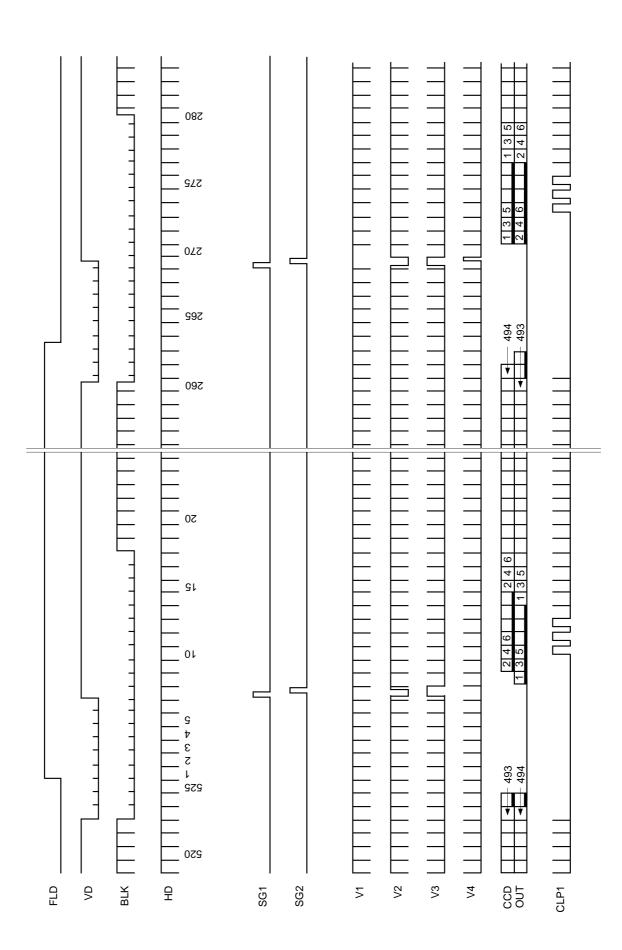
**Drive Circuit** 

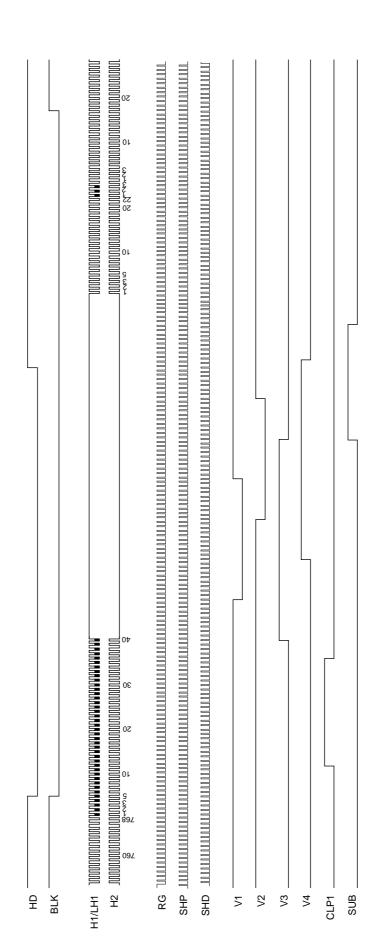
(Includes lens characteristics, excludes light source characteristics)











# Notes on Handling

1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

# 2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.
- 3) Dust and dirt protection

Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operation as required, and use them.

- a) Operate in clean environments (around class 1000 is appropriate).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.
- 4) Do not expose to strong light (sun rays) for long periods, color filters will be discolored. For continuous using under cruel condition exceeding the normal using condition, consult our company.
- 5) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- 6) CCD image sensors are precise optical equipment that should not be subject to too much mechanical shocks.

